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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	72MHz
Connectivity	CANbus, I²C, IrDA, LINbus, SPI, UART/USART
Peripherals	DMA, I²S, POR, PWM, WDT
Number of I/O	51
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	2V ~ 3.6V
Data Converters	A/D 15x12b; D/A 1x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	64-LQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f303r8t6tr

Contents

remains in reset mode when the monitored supply voltage is below a specified threshold, $V_{POR/PDR}$, without the need for an external reset circuit.

- The POR monitors only the V_{DD} supply voltage. During the startup phase it is required that V_{DDA} should arrive first and be greater than or equal to V_{DD}.
- The PDR monitors both the V_{DD} and V_{DDA} supply voltages, however the V_{DDA} power supply supervisor can be disabled (by programming a dedicated Option bit) to reduce the power consumption if the application design ensures that V_{DDA} is higher than or equal to V_{DD}.

The device features an embedded programmable voltage detector (PVD) that monitors the V_{DD} power supply and compares it to the V_{PVD} threshold. An interrupt can be generated when V_{DD} drops below the V_{PVD} threshold and/or when V_{DD} is higher than the V_{PVD} threshold. The interrupt service routine can then generate a warning message and/or put the MCU into a safe state. The PVD is enabled by software.

3.4.3 Voltage regulator

The regulator has three operation modes: main (MR), low-power (LPR), and power-down.

- The MR mode is used in the nominal regulation mode (Run)
- The LPR mode is used in Stop mode.
- The power-down mode is used in Standby mode: the regulator output is in high impedance, and the kernel circuitry is powered down thus inducing zero consumption.

The voltage regulator is always enabled after reset. It is disabled in Standby mode.

3.4.4 Low-power modes

The STM32F303x6/8 supports three low-power modes to achieve the best compromise between low power consumption, short startup time and available wakeup sources:

- **Sleep mode**

  In Sleep mode, only the CPU is stopped. All peripherals continue to operate and can wake up the CPU when an interrupt/event occurs.
- **Stop mode**

  Stop mode achieves the lowest power consumption while retaining the content of SRAM and registers. All clocks in the 1.8 V domain are stopped, the PLL, the HSI RC and the HSE crystal oscillators are disabled. The voltage regulator can also be put either in normal or in low-power mode.

  The device can be woken up from Stop mode by any of the EXTI line. The EXTI line source can be one of the 16 external lines, the PVD output, the RTC alarm, COMPx, I^2C or USARTx.
- **Standby mode**

  The Standby mode is used to achieve the lowest power consumption. The internal voltage regulator is switched off so that the entire 1.8 V domain is powered off. The PLL, the HSI RC and the HSE crystal oscillators are also switched off. After entering Standby mode, SRAM and register contents are lost except for registers in the Backup domain and Standby circuitry.

  The device exits Standby mode when an external reset (NRST pin), an IWDG reset, a rising edge on the WKUP pin, or an RTC alarm occurs.

Note: The RTC, the IWDG, and the corresponding clock sources are not stopped by entering Stop or Standby mode.

high-speed APB domains is 72 MHz, while the maximum allowed frequency of the low-speed APB domain is 36 MHz.

TIM1 maximum frequency is 144 MHz.

independently. A pending register maintains the status of the interrupt requests. The EXTI can detect an external line with a pulse width shorter than the internal clock period. Up to 51 GPIOs can be connected to the 16 external interrupt lines.

3.10 Fast analog-to-digital converter (ADC)

Two 5 MSPS fast analog-to-digital converters, with selectable resolution between 12 and 6 bit, are embedded in the STM32F303x6/8 family devices. The ADCs have up to 21 external channels. Some of the external channels are shared between ADC1 and ADC2, performing conversions in single-shot or scan modes. The channels can be configured to be either single-ended input or differential input. In scan mode, automatic conversion is performed on a selected group of analog inputs.

The ADCs also have internal channels: temperature sensor connected to ADC1 channel 16, V_{BAT}/2 connected to ADC1 channel 17, voltage reference V_{REFINT} connected to both ADC1 and ADC2 channel 18 and VOPAMP2 connected to ADC2 channel 17.

Additional logic functions embedded in the ADC interface allow:

- Simultaneous sample and hold
- Interleaved sample and hold
- Single-shunt phase current reading techniques.

Three analog watchdogs are available per ADC. The ADC can be served by the DMA controller.

The analog watchdog feature allows very precise monitoring of the converted voltage of one, some or all selected channels. An interrupt is generated when the converted voltage is outside the programmed thresholds.

The events generated by the general-purpose timers (TIM2, TIM3, TIM6, TIM15) and the advanced-control timer (TIM1) can be internally connected to the ADC start trigger and injection trigger, respectively, to allow the application to synchronize A/D conversion and timers.

3.10.1 Temperature sensor

The temperature sensor (TS) generates a voltage V_{SENSE} that varies linearly with temperature.

The temperature sensor is internally connected to the ADC1_IN16 input channel which is used to convert the sensor output voltage into a digital value.

The sensor provides good linearity but it has to be calibrated to obtain good overall accuracy of the temperature measurement. As the offset of the temperature sensor varies from chip to chip due to process variation, the uncalibrated internal temperature sensor is suitable for applications that detect temperature changes only.

To improve the accuracy of the temperature sensor measurement, each device is individually factory-calibrated by ST. The temperature sensor factory calibration data are stored by ST in the system memory area, accessible in read-only mode.

3.10.2 Internal voltage reference (VREFINT)

The internal voltage reference (VREFINT) provides a stable (bandgap) voltage output for the ADC and Comparators. VREFINT is internally connected to the ADC1_IN18 and ADC2_IN18

3.14.4 Independent watchdog

The independent watchdog is based on a 12-bit downcounter and 8-bit prescaler. It is clocked from an independent 40 kHz internal RC and as it operates independently from the main clock, it can operate in Stop and Standby modes. It can be used either as a watchdog to reset the device when a problem occurs, or as a free running timer for application timeout management. It is hardware or software configurable through the option bytes. The counter can be frozen in debug mode.

3.14.5 Window watchdog

The window watchdog is based on a 7-bit downcounter that can be set as free running. It can be used as a watchdog to reset the device when a problem occurs. It is clocked from the main clock. It has an early warning interrupt capability and the counter can be frozen in debug mode.

3.14.6 SysTick timer

This timer is dedicated to real-time operating systems, but could also be used as a standard down counter. It features:

- A 24-bit down counter
- Autoreload capability
- Maskable system interrupt generation when the counter reaches 0.
- Programmable clock source

3.15 Real-time clock (RTC) and backup registers

The RTC and the 5 backup registers are supplied through a switch that takes power from either the V_{DD} supply when present or the VBAT pin. The backup registers are five 32-bit registers used to store 20 bytes of user application data when V_{DD} power is not present.

They are not reset by a system or power reset, or when the device wakes up from Standby mode.

The RTC is an independent BCD timer/counter. It supports the following features:

- Calendar with subsecond, seconds, minutes, hours (12 or 24 format), week day, date, month, year, in BCD (binary-coded decimal) format.
- Reference clock detection: a more precise second source clock (50 or 60 Hz) can be used to enhance the calendar precision.
- Automatic correction for 28, 29 (leap year), 30, and 31 days of the month.
- Two programmable alarms with wake up from Stop and Standby mode capability.
- On-the-fly correction from 1 to 32767 RTC clock pulses. This can be used to synchronize it with a master clock.
- Digital calibration circuit with 1 ppm resolution, to compensate for quartz crystal inaccuracy.
- Two anti-tamper detection pins with programmable filter. The MCU can be woken up from Stop and Standby modes on tamper event detection.
- Timestamp feature which can be used to save the calendar content. This function can be triggered by an event on the timestamp pin, or by a tamper event. The MCU can be

Table 14. STM32F303x6/8 pin definitions (continued)

Pin Number			Pin name (function after reset)	Pin type	I/O structure	Pin functions	
LQFP 32	LQFP 48	LQFP 64				Alternate functions	Additional functions
3	6	6	PF1 / OSC_OUT	I/O	FT	-	OSC_OUT
4	7	7	NRST	I/O	RST	Device reset input / internal reset output (active low)	
-	-	8	PC0	I/O	TTa	EVENTOUT, TIM1_CH1	ADC12_IN6
-	-	9	PC1	I/O	TTa	EVENTOUT, TIM1_CH2	ADC12_IN7
-	-	10	PC2	I/O	TTa	EVENTOUT, TIM1_CH3	ADC12_IN8
-	-	11	PC3	I/O	TTa	EVENTOUT, TIM1_CH4, TIM1_BKIN2	ADC12_IN9
-	8	12	VSSA/VREF-	S	-	Analog ground/Negative reference voltage	
5	9	13	VDDA/VREF+	S	-	Analog power supply/Positive reference voltage	
6	10	14	PA0	I/O	TTa	TIM2_CH1/ TIM2_ETR, TSC_G1_IO1, USART2_CTS, EVENTOUT	ADC1_IN1[(2)], RTC_TAMP2/WKUP1
7	11	15	PA1	I/O	TTa	TIM2_CH2, TSC_G1_IO2, USART2_RTS_DE, TIM15_CH1N, EVENTOUT	ADC1_IN2[(2)], RTC_REFIN
8	12	16	PA2	I/O	TTa	TIM2_CH3, TSC_G1_IO3, USART2_TX, COMP2_OUT, TIM15_CH1, EVENTOUT	ADC1_IN3[(2)], COMP2_INM
9	13	17	PA3	I/O	TTa	TIM2_CH4, TSC_G1_IO4, USART2_RX, TIM15_CH2, EVENTOUT	ADC1_IN4[(2)]
-	-	18	VSS	S	-	-	-
-	-	19	VDD	S	-	-	-
10	14	20	PA4[(3)]	I/O	TTa	TIM3_CH2, TSC_G2_IO1, SPI1_NSS, USART2_CK, EVENTOUT	ADC2_IN1[(2)], DAC1_OUT1, COMP2_INM4, COMP4_INM4, COMP6_INM4
11	15	21	PA5[(3)]	I/O	TTa	TIM2_CH1/ TIM2_ETR, TSC_G2_IO2, SPI1_SCK, EVENTOUT	ADC2_IN2[(2)], DAC1_OUT2, OPAMP2_VINM

Table 15. Alternate functions

Port		AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7	AF8	AF9	AF10	AF11	AF12	AF13	AF14	AF15
		SYS_AF	TIM2/TIM15/ TIM16/TIM17/ EVENT	TIM1/TIM3/ TIM15/ TIM16	TSC	I2C1/TIM1	SPI1/Infrared	TIM1/Infrared	USART1/USA RT2/USART3/ GPCOMP6	GPCOMP2/ GPCOMP4/ GPCOMP6	CAN/TIM1/ TIM15	TIM2/TIM3 /TIM17	TIM1	TIM1	OPAMP2	-	EVENT
Port A	PA0	-	TIM2_CH1/TI M2_ETR	-	TSC_G1_IO1	-	-	-	USART2_CTS	-	-	-	-	-	-	-	EVENTOUT
	PA1	-	TIM2_CH2	-	TSC_G1_IO2	-	-	-	USART2_RTS _DE	-	TIM15_CH1N	-	-	-	-	-	EVENTOUT
	PA2	-	TIM2_CH3	-	TSC_G1_IO3	-	-	-	USART2_TX	COMP2_OUT	TIM15_CH1	-	-	-	-	-	EVENTOUT
	PA3	-	TIM2_CH4	-	TSC_G1_IO4	-	-	-	USART2_RX	-	TIM15_CH2	-	-	-	-	-	EVENTOUT
	PA4	-	-	TIM3_CH2	TSC_G2_IO1	-	SPI1_NSS	-	USART2_CK	-	-	-	-	-	-	-	EVENTOUT
	PA5	-	TIM2_CH1/TI M2_ETR	-	TSC_G2_IO2	-	SPI1_SCK	-	-	-	-	-	-	-	-	-	EVENTOUT
	PA6	-	TIM16_CH1	TIM3_CH1	TSC_G2_IO3	-	SPI1_MISO	TIM1_BKIN	-	-	-	-	-	-	-	-	EVENTOUT
	PA7	-	TIM17_CH1	TIM3_CH2	TSC_G2_IO4	-	SPI1_MOSI	TIM1_CH1N	-	-	-	-	-	-	-	-	EVENTOUT
	PA8	MCO	-	-	-	-	-	TIM1_CH1	USART1_CK	-	-	-	-	-		v	EVENTOUT
	PA9	-	-	-	TSC_G4_IO1	-	-	TIM1_CH2	USART1_TX	-	TIM15_BKIN	TIM2_CH3	-	-		-	EVENTOUT
	PA10	-	TIM17_BKIN	-	TSC_G4_IO2	-	-	TIM1_CH3	USART1_RX	COMP6_OUT	-	TIM2_CH4	-	-		-	EVENTOUT
	PA11	-	-	-	-	-	-	TIM1_CH1N	USART1_CTS	-	CAN_RX	-	TIM1_CH4	TIM1_BKIN2		-	EVENTOUT
	PA12	-	TIM16_CH1	-	-	-	-	TIM1_CH2N	USART1_RTS _DE	COMP2_OUT	CAN_TX	-	TIM1_ETR	-		-	EVENTOUT
	PA13	JTMS/SWDAT	TIM16_CH1N	-	TSC_G4_IO3	-	IR_OUT	-	USART3_CTS	-	-	-	-	-	-	-	EVENTOUT
	PA14	JTCK/SWCLK	-	-	TSC_G4_IO4	I2C1_SDA	-	TIM1_BKIN	USART2_TX	-	-	-	-	-	-	-	EVENTOUT
	PA15	JTDI	TIM2_CH1/ TIM2_ETR	-	TSC_SYNC	I2C1_SCL	SPI1_NSS	-	USART2_RX	-	TIM1_BKIN	-	-	-		-	EVENTOUT
Port B	PB0	-	-	TIM3_CH3	TSC_G3_IO2	-	-	TIM1_CH2N	-	-	-	-	-	-	-	-	EVENTOUT
	PB1	-	-	TIM3_CH4	TSC_G3_IO3	-	-	TIM1_CH3N	-	COMP4_OUT	-	-	-	-		-	EVENTOUT
	PB2	-	-	-	TSC_G3_IO4	-	-	-	-	-	-	-	-	-		-	EVENTOUT
	PB3	JTDO/TRACE SWO	TIM2_CH2	-	TSC_G5_IO1	-	SPI1_SCK	-	USART2_TX	-	-	TIM3_ETR	-			-	EVENTOUT
	PB4	NJTRST	TIM16_CH1	TIM3_CH1	TSC_G5_IO2	-	SPI1_MISO	-	USART2_RX	-	-	TIM17_BK IN	-	-		-	EVENTOUT
	PB5	-	TIM16_BKIN	TIM3_CH2	-	I2C1_SMBA	SPI1_MOSI	-	USART2_CK	-	-	TIM17_CH 1	-	-		-	EVENTOUT
	PB6	-	TIM16_CH1N	-	TSC_G5_IO3	I2C1_SCL	-	-	USART1_TX	-	-	-	-			-	EVENTOUT
	PB7	-	TIM17_CH1N	-	TSC_G5_IO4	I2C1_SDA	-	-	USART1_RX	-	-	TIM3_CH4	-	-		-	EVENTOUT
	PB8	-	TIM16_CH1	-	TSC_SYNC	I2C1_SCL	-	-	USART3_RX	-	CAN_RX	-	-	TIM1_BKIN		-	EVENTOUT
	PB9	-	TIM17_CH1	-	-	I2C1_SDA	-	IR_OUT	USART3_TX	COMP2_OUT	CAN_TX	-	-	-		-	EVENTOUT

Table 16. STM32F303x6/8 peripheral register boundary addresses

Bus	Boundary address	Size (bytes)	Peripheral
AHB3	0x5000 0000 - 0x5000 03FF	1 K	ADC1 - ADC2
-	0x4800 1800 - 0x4FFF FFFF	~132 M	Reserved
AHB2	0x4800 1400 - 0x4800 17FF	1 K	GPIOF
-	0x4800 1000 - 0x4800 13FF	1 K	Reserved
AHB2	0x4800 0C00 - 0x4800 0FFF	1 K	GPIOD
	0x4800 0800 - 0x4800 0BFF	1 K	GPIOC
	0x4800 0400 - 0x4800 07FF	1 K	GPIOB
	0x4800 0000 - 0x4800 03FF	1 K	GPIOA
-	0x4002 4400 - 0x47FF FFFF	~128 M	Reserved
AHB1	0x4002 4000 - 0x4002 43FF	1 K	TSC
	0x4002 3400 - 0x4002 3FFF	3 K	Reserved
	0x4002 3000 - 0x4002 33FF	1 K	CRC
	0x4002 2400 - 0x4002 2FFF	3 K	Reserved
	0x4002 2000 - 0x4002 23FF	1 K	Flash interface
	0x4002 1400 - 0x4002 1FFF	3 K	Reserved
	0x4002 1000 - 0x4002 13FF	1 K	RCC
	0x4002 0400 - 0x4002 0FFF	3 K	Reserved
	0x4002 0000 - 0x4002 03FF	1 K	DMA1
-	0x4001 8000 - 0x4001 FFFF	32 K	Reserved
APB2	0x4001 4C00 - 0x4001 73FF	12 K	Reserved
	0x4001 4800 - 0x4001 4BFF	1 K	TIM17
	0x4001 4400 - 0x4001 47FF	1 K	TIM16
	0x4001 4000 - 0x4001 43FF	1 K	TIM15
	0x4001 3C00 - 0x4001 3FFF	1 K	Reserved
	0x4001 3800 - 0x4001 3BFF	1 K	USART1
	0x4001 3400 - 0x4001 37FF	1 K	Reserved
	0x4001 3000 - 0x4001 33FF	1 K	SPI1
	0x4001 2C00 - 0x4001 2FFF	1 K	TIM1
	0x4001 0800 - 0x4001 2BFF	9 K	Reserved
	0x4001 0400 - 0x4001 07FF	1 K	EXTI
	0x4001 0000 - 0x4001 03FF	1 K	SYSCFG + COMP + OPAMP
-	0x4000 9C00 - 0x4000 FFFF	25 K	Reserved

Table 16. STM32F303x6/8 peripheral register boundary addresses (continued)

Bus	Boundary address	Size (bytes)	Peripheral
APB1	0x4000 9800 - 0x4000 9BFF	1 K	DAC2
	0x4000 7800 - 0x4000 97FF	8 K	Reserved
	0x4000 7400 - 0x4000 77FF	1 K	DAC1
	0x4000 7000 - 0x4000 73FF	1 K	PWR
	0x4000 6800 - 0x4000 6FFF	2 K	Reserved
	0x4000 6400 - 0x4000 67FF	1 K	bxCAN
	0x4000 5800 - 0x4000 63FF	3 K	Reserved
	0x4000 5400 - 0x4000 57FF	1 K	I2C1
	0x4000 4C00 - 0x4000 53FF	2 K	Reserved
	0x4000 4800 - 0x4000 4BFF	1 K	USART3
	0x4000 4400 - 0x4000 47FF	1 K	USART2
	0x4000 3400 - 0x4000 43FF	2 K	Reserved
	0x4000 3000 - 0x4000 33FF	1 K	IWDG
	0x4000 2C00 - 0x4000 2FFF	1 K	WWDG
	0x4000 2800 - 0x4000 2BFF	1 K	RTC
	0x4000 1800 - 0x4000 27FF	4 K	Reserved
	0x4000 1400 - 0x4000 17FF	1 K	TIM7
	0x4000 1000 - 0x4000 13FF	1 K	TIM6
	0x4000 0800 - 0x4000 0FFF	2 K	Reserved
	0x4000 0400 - 0x4000 07FF	1 K	TIM3
	0x4000 0000 - 0x4000 03FF	1 K	TIM2
-	0x2000 3000 - 3FFF FFFF	~512 M	Reserved
-	0x2000 0000 - 0x2000 2FFF	12 K	SRAM
-	0x1FFF F800 - 0x1FFF FFFF	2 K	Option bytes
-	0x1FFF D800 - 0x1FFF F7FF	8 K	System memory
-	0x1000 2000 - 0x1FFF D7FF	~256 M	Reserved
-	0x1000 0000 - 0x1000 0FFF	4 K	CCM RAM
-	0x0804 0000 - 0x0FFF FFFF	~128 M	Reserved
-	0x0800 0000 - 0x0800 FFFF	64 K	Main Flash memory
-	0x0004 0000 - 0x07FF FFFF	~128 M	Reserved
-	0x0000 000 - 0x0000 FFFF	64 K	Main Flash memory, system memory or SRAM depending on BOOT configuration

6.1.7 Measurement of the current consumption

Figure 11. Scheme of the current-consumption measurement

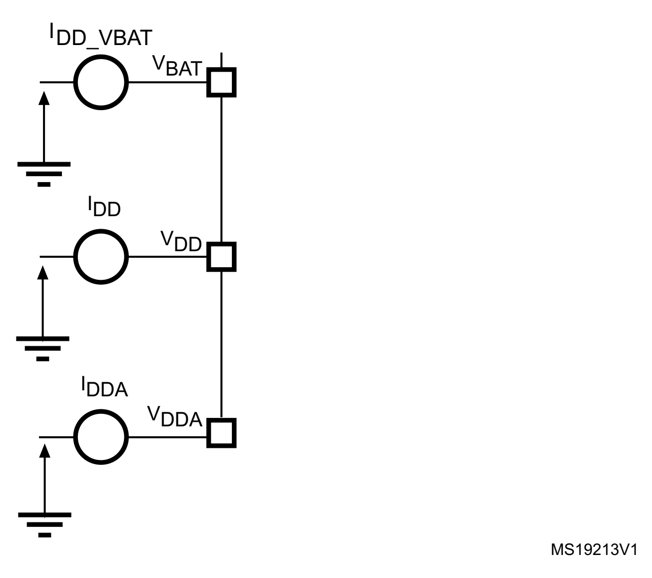


Table 25. Internal reference voltage calibration values

Calibration value name	Description	Memory address
V_{REFINT_CAL}	Raw data acquired at temperature of 30 °C V_{DDA}= 3.3 V	0x1FFF F7BA - 0x1FFF F7BB

6.3.5 Supply current characteristics

The current consumption is a function of several parameters and factors such as the operating voltage, ambient temperature, I/O pin loading, device software configuration, operating frequencies, I/O pin switching rate, program location in memory and executed binary code.
The current consumption is measured as described in *Figure 11: Scheme of the current-consumption measurement*.
All Run-mode current consumption measurements given in this section are performed with a reduced code that gives a consumption equivalent to CoreMark code.

Note: The total current consumption is the sum of IDD and IDDA.

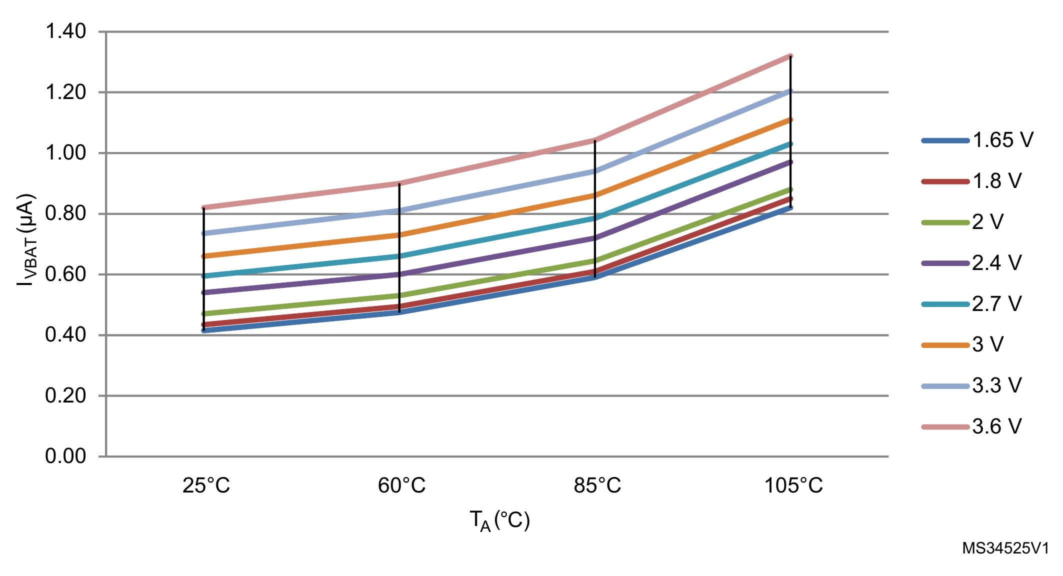
Typical and maximum current consumption

The MCU is placed under the following conditions:

- All I/O pins are in input mode with a static value at V_{DD} or V_{SS} (no load)
- All peripherals are disabled except when explicitly mentioned
- The Flash memory access time is adjusted to the f_{HCLK} frequency (0 wait state from 0 to 24 MHz,1 wait state from 24 to 48 MHz and 2 wait states from 48 to 72 MHz)
- Prefetch in ON (reminder: this bit must be set before clock setting and bus prescaling)
- When the peripherals are enabled $f_{PCLK2} = f_{HCLK}$ and $f_{PCLK1} = f_{HCLK/2}$
- When $f_{HCLK} > 8$ MHz, the PLL is ON and the PLL input is equal to HSI/2 (4 MHz) or HSE (8 MHz) in bypass mode.

The parameters given in *Table 26* to *Table 30* are derived from tests performed under ambient temperature and supply voltage conditions summarized in *Table 20*.

Figure 12. Typical V_{BAT} current consumption (LSE and RTC ON/LSEDRV[1:0] = ’00’)



Typical current consumption

The MCU is placed under the following conditions:

- $V_{DD} = V_{DDA} = 3.3$ V
- All I/O pins available on each package are in analog input configuration
- The Flash access time is adjusted to f_{HCLK} frequency (0 wait states from 0 to 24 MHz, 1 wait state from 24 to 48 MHz and 2 wait states from 48 MHz to 72 MHz), and Flash prefetch is ON
- When the peripherals are enabled, $f_{APB1} = f_{AHB/2}$, $f_{APB2} = f_{AHB}$
- PLL is used for frequencies greater than 8 MHz
- AHB prescaler of 2, 4, 8,16 and 64 is used for the frequencies 4 MHz, 2 MHz, 1 MHz, 500 kHz and 125 kHz respectively.

Table 32. Typical current consumption in Run mode, code with data processing running from Flash memory

Symbol	Parameter	Conditions	f_{HCLK}	Typ.		Unit
				Peripherals enabled	Peripherals disabled	
I_{DD}	Supply current in Run mode from V_{DD} supply	Running from HSE crystal clock 8 MHz, code executing from Flash	72 MHz	70.6	25.2	mA
			64 MHz	60.3	22.6	
			48 MHz	46.0	17.3	
			32 MHz	31.3	12.0	
			24 MHz	25.0	9.3	
			16 MHz	16.2	6.5	
			8 MHz	8.4	3.55	
			4 MHz	4.75	2.21	
			2 MHz	2.81	1.52	
			1 MHz	1.82	1.17	
			500 kHz	1.34	0.94	
			125 kHz	0.93	0.82	
I_{DDA}(1) (2)	Supply current in Run mode from V_{DDA} supply		72 MHz	240.0	234.0	µA
			64 MHz	209.9	208.6	
			48 MHz	154.5	153.5	
			32 MHz	104.1	103.6	
			24 MHz	80.2	80.0	
			16 MHz	56.8	56.6	
			8 MHz	1.14	1.14	
			4 MHz	1.14	1.14	
			2 MHz	1.14	1.14	
			1 MHz	1.14	1.14	
			500 kHz	1.14	1.14	
			125 kHz	1.14	1.14	

1. V_{DDA} supervisor is OFF.
2. When peripherals are enabled, the power consumption of the analog part of peripherals such as ADC, DAC, Comparators, OpAmp etc. is not included. Refer to the tables of characteristics in the subsequent sections.

On-chip peripheral current consumption

The MCU is placed under the following conditions:

- All I/O pins are in analog input configuration
- All peripherals are disabled unless otherwise mentioned
- The given value is calculated by measuring the current consumption:
  - With all peripherals clocked off
  - With only one peripheral clocked on
- Ambient operating temperature at 25°C and $V_{DD} = V_{DDA} = 3.3$ V

Table 35. Peripheral current consumption

Peripheral	Typical consumption(1)	Unit
	I_{DD}	
BusMatrix (2)	11.1	µA/MHz
DMA1	8.0	-
CRC	2.1	-
GPIOA	8.7	-
GPIOB	8.4	-
GPIOC	8.4	-
GPIOD	2.6	-
GPIOF	1.7	-
TSC	4.7	-
ADC1&2	17.4	-
APB2-Bridge (3)	3.3	-
SYSCFG	4.2	-
TIM1	32.3	-
USART1	20.3	-
TIM15	13.8	-
TIM16	9.7	-
TIM17	10.3	-
APB1-Bridge (3)	5.3	-
TIM2	43.4	-
TIM3	34.0	-
TIM6	9.7	-
TIM7	10.3	-
WWDG	6.9	-
USART2	18.8	-
USART3	19.1	-
I2C1	13.3	-

Table 38. High-speed external user clock characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
f_{HSE_ext}	User external clock source frequency(1)	-	1	8	32	MHz
V_{HSEH}	OSC_IN input pin high-level voltage		$0.7V_{DD}$	-	V_{DD}	V
V_{HSEL}	OSC_IN input pin low-level voltage		V_{SS}	-	$0.3V_{DD}$	
$t_{w(HSEH)}$ $t_{w(HSEL)}$	OSC_IN high or low time(1)		15	-	-	ns
$t_{r(HSE)}$ $t_{f(HSE)}$	OSC_IN rise or fall time(1)		-	-	20	

1. Guaranteed by design, not tested in production.

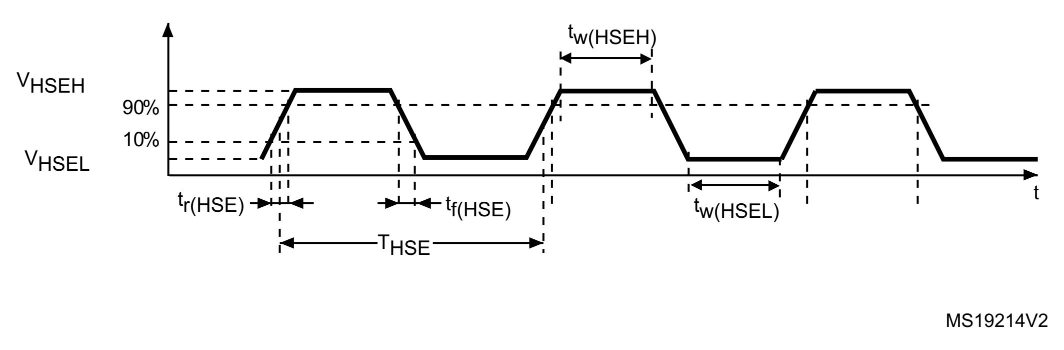


Figure 13. High-speed external clock source AC timing diagram

Low-speed external user clock generated from an external source

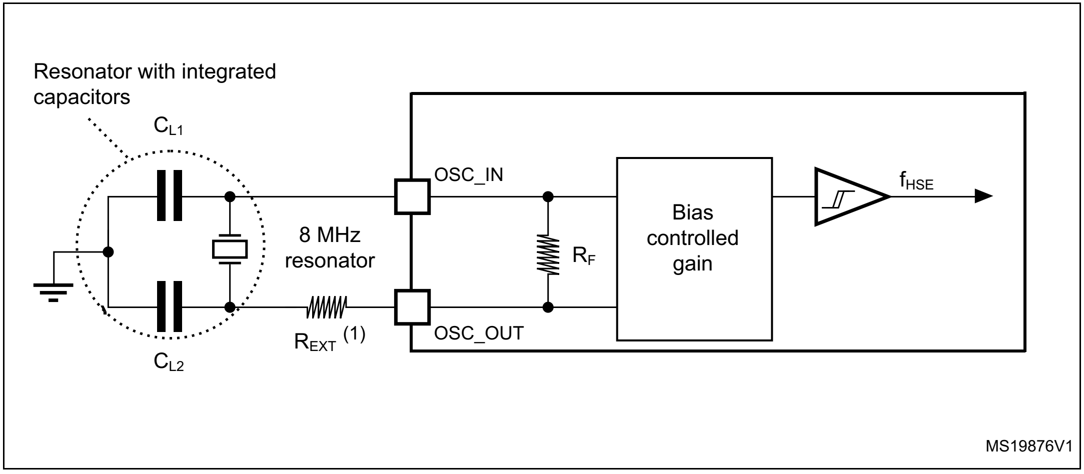
In bypass mode the LSE oscillator is switched off and the input pin is a standard GPIO. The external clock signal has to respect the I/O characteristics in *Section 6.3.14*. However, the recommended clock input waveform is shown in *Figure 14*

Table 39. Low-speed external user clock characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
f_{LSE_ext}	User External clock source frequency(1)	-	-	32.768	1000	kHz
V_{LSEH}	OSC32_IN input pin high-level voltage		$0.7V_{DD}$	-	V_{DD}	V
V_{LSEL}	OSC32_IN input pin low-level voltage		V_{SS}	-	$0.3V_{DD}$	
$t_{w(LSEH)}$ $t_{w(LSEL)}$	OSC32_IN high or low time(1)		450	-	-	ns
$t_{r(LSE)}$ $t_{f(LSE)}$	OSC32_IN rise or fall time(1)		-	-	50	

1. Guaranteed by design, not tested in production.

Figure 16. Typical application with a 32.768 kHz crystal



Note: *An external resistor is not required between OSC32_IN and OSC32_OUT and it is forbidden to add one.*

6.3.8 Internal clock source characteristics

The parameters given in *Table 42* are derived from tests performed under ambient temperature and supply voltage conditions summarized in *Table 20*.

High-speed internal (HSI) RC oscillator

Table 42. HSI oscillator characteristics(1)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
f_{HSI}	Frequency	-	-	8	-	MHz
TRIM	HSI user trimming step	-	-	-	1(2)	%
$DuCy_{(HSI)}$	Duty cycle	-	45(2)	-	55(2)	%
ACC_{HSI}	Accuracy of the HSI oscillator (factory calibrated)	T_A = –40 to 105 °C	–2.8(3)	-	3.8(3)	%
		T_A = –10 to 85 °C	–1.9(3)	-	2.3(3)	
		T_A = 0 to 85 °C	-1.9(3)	-	2(3)	
		T_A = 0 to 70 °C	-1.3(3)	-	2(3)	
		T_A = 0 to 55 °C	–1(3)	-	2(3)	
		T_A = 25 °C(4)	–1	-	1	
$t_{su(HSI)}$	HSI oscillator startup time	-	1(2)	-	2(2)	µs
$I_{DDA(HSI)}$	HSI oscillator power consumption	-	-	80	100(2)	µA

1. V_{DDA} = 3.3 V, T_A = –40 to 105 °C unless otherwise specified.
2. Guaranteed by design, not tested in production.
3. Data based on characterization results, not tested in production.
4. Factory calibrated, parts not soldered

Table 48. EMI characteristics

Symbol	Parameter	Conditions	Monitored frequency band	Max vs. [f_{HSE}/f_{HCLK}] 8/72 MHz	Unit
S_{EMI}	Peak level	V_{DD} = 3.6 V, T_A =25 °C, LQFP100 package compliant with IEC 61967-2	0.1 to 30 MHz	5	dBµV
			30 to 130 MHz	9	
			130 MHz to 1GHz	31	
			SAE EMI Level	4	-

6.3.12 Electrical sensitivity characteristics

Based on three different tests (ESD, LU) using specific measurement methods, the device is stressed to determine its performance in terms of electrical sensitivity.

Electrostatic discharge (ESD)

Electrostatic discharges (a positive then a negative pulse separated by 1 second) are applied to the pins of each sample according to each pin combination. The sample size depends on the number of supply pins in the device (3 parts × (n+1) supply pins). This test conforms to the JESD22-A114/C101 standard.

Table 49. ESD absolute maximum ratings

Symbol	Ratings	Conditions	Class	Maximum value[1]	Unit
$V_{ESD(HBM)}$	Electrostatic discharge voltage (human body model)	T_A = +25 °C, conforming to JESD22-A114	2	2000	V
$V_{ESD(CDM)}$	Electrostatic discharge voltage (charge device model)	T_A = +25 °C, conforming to JESD22-C101	II	250	

1. Data based on characterization results, not tested in production.

Static latch-up

Two complementary static tests are required on six parts to assess the latch-up performance:

- A supply overvoltage is applied to each power supply pin
- A current injection is applied to each input, output and configurable I/O pin

These tests are compliant with EIA/JESD 78A IC latch-up standard.

Table 50. Electrical sensitivities

Symbol	Parameter	Conditions	Class
LU	Static latch-up class	T_A = +105 °C conforming to JESD78A	II level A

Table 57. IWDG min./max. timeout period at 40 kHz (LSI) (1)

Prescaler divider	PR[2:0] bits	Min. timeout (ms) RL[11:0]= 0x000	Max. timeout (ms) RL[11:0]= 0xFFF
/4	0	0.1	409.6
/8	1	0.2	819.2
/16	2	0.4	1638.4
/32	3	0.8	3276.8
/64	4	1.6	6553.6
/128	5	3.2	13107.2
/256	7	6.4	26214.4

1. These timings are given for a 40 kHz clock but the microcontroller's internal RC frequency can vary from 30 to 60 kHz. Moreover, given an exact RC oscillator frequency, the exact timings still depend on the phasing of the APB interface clock versus the LSI clock so that there is always a full RC period of uncertainty.

Table 58. WWDG min./max. timeout value at 72 MHz (PCLK)(1)

Prescaler	WDGTB	Min. timeout value	Max. timeout value
1	0	0.05687	3.6409
2	1	0.1137	7.2817
4	2	0.2275	14.564
8	3	0.4551	29.127

1. Guaranteed by design, not tested in production.

6.3.17 Communication interfaces

I^{2}C interface characteristics

The I^{2}C interface meets the timings requirements of the I^{2}C-bus specification and user manual rev. 03 for:

- Standard-mode (Sm): with a bit rate up to 100 Kbit/s
- Fast-mode (Fm): with a bit rate up to 400 Kbit/s
- Fast-mode Plus (Fm+): with a bit rate up to 1 Mbit/s.

The I^{2}C timings requirements are guaranteed by design when the I^{2}C peripheral is properly configured (refer to Reference manual).

The SDA and SCL I/O requirements are met with the following restrictions: the SDA and SCL I/O pins are not "true" open-drain. When configured as open-drain, the PMOS connected between the I/O pin and VDD is disabled, but is still present. Only FTf I/O pins support Fm+ low-level output current maximum requirement. Refer to *Section 6.3.14: I/O port characteristics* for the I^{2}C I/O characteristics.

All I^{2}C SDA and SCL I/Os embed an analog filter. Refer to the table below for the analog filter characteristics:

Figure 24. SPI timing diagram - slave mode and CPHA = 0

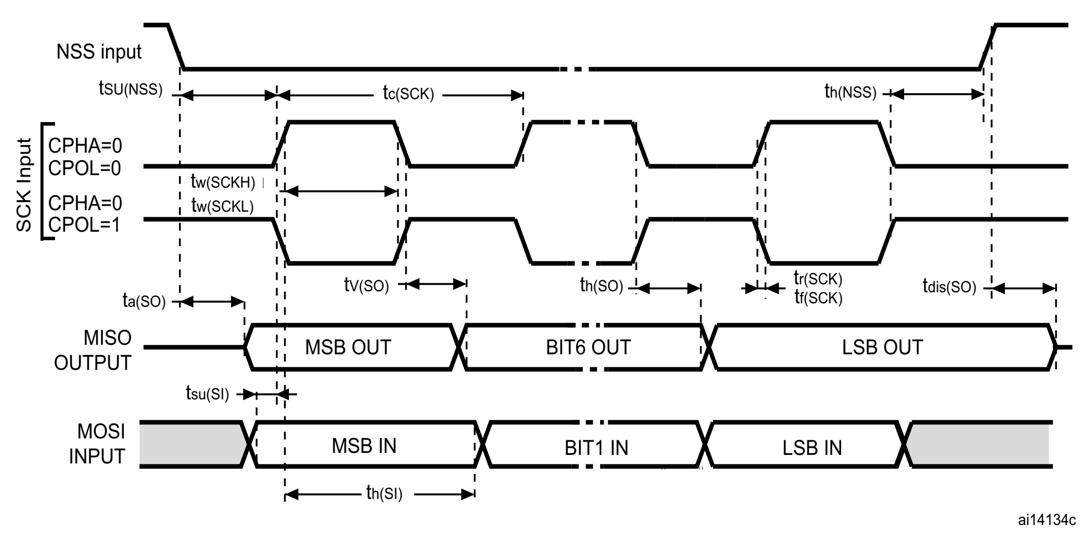
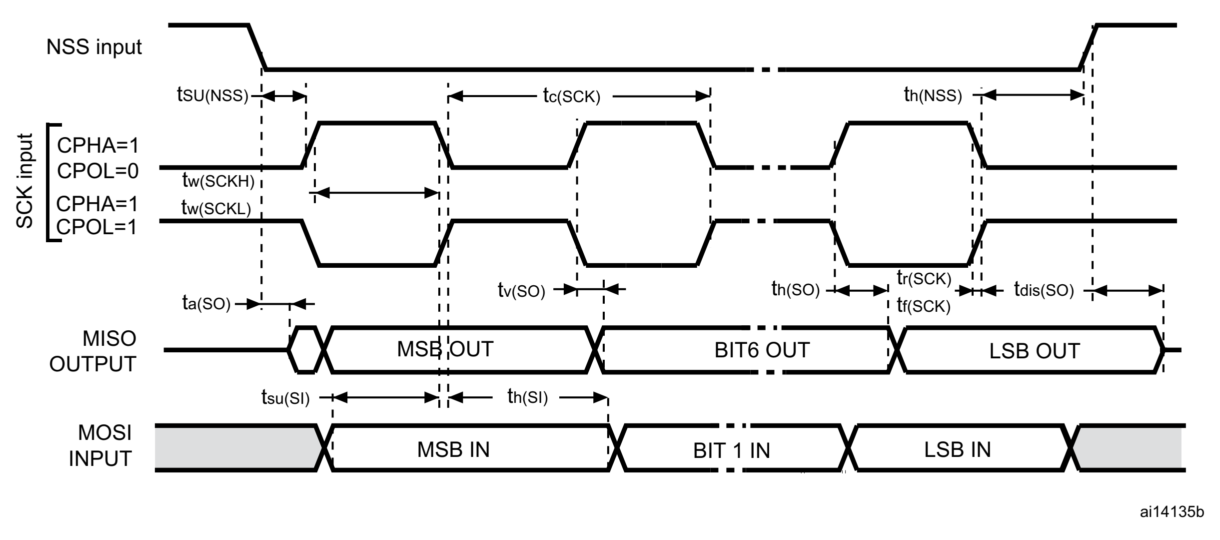


Figure 25. SPI timing diagram - slave mode and CPHA = 1(1)



1. Measurement points are done at $0.5V_{DD}$ and with external C_L = 30 pF.